

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/617,642	PARK ET AL.	
Examiner	Art Unit	
Minh Dinh	2132	

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Class	Subclass	Date	Examiner			
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INTERFERENCE SEARCHED					
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
713/160,162 380/259-262,270,273-274,37,42-44,28 (text search only for all - see search history printout)	11/4/2006 (4 23/07)	(MD)			
EAST (US-PGPUB, USPAT, EPO, JPO, DERWENT, IBM_TDB) - see search history printout	_11/4/2006 (4/23 <i>l</i> 07)	MD (M0)			
NPL (ACM, GOOGLE, IEEE)	11/4/2006 (H13/07)	(MD)			
Inventor Name Search	11/4/2006 (4(23/07)	MD MD			
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